

CA3060A/...

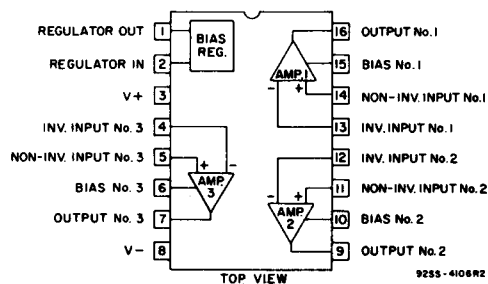
Operational Transconductance
Amplifier Arrays

The CA3060 Slash (/) Series type is supplied in the 16-lead dual-in-line ceramic package (D suffix).

TABLE A. POST BURN-IN, FINAL ELECTRICAL AND GROUP A SAMPLING TESTS

CHARACTERISTIC	SYMBOL	TEST CONDITIONS	LIMITS						UNITS
			MIN.			MAX.			
			-55° C	+25° C	+125° C	-55° C	+25° C	+125° C	
Input Offset Voltage	V _{IO}	V+ = +15 V, V- = -15 V I _{ABC} = 100 μA	-6	-5	-6	+6	+5	+6	mV
Input Bias Current	I _{IB}		—	—	—	10000	5000	10000	nA
Input Offset Current	I _{IO}		-2000	-1000	-2000	2000	1000	2000	nA
Input Offset Voltage Sensitivity	ΔV _{IO} /ΔV+		-150	-150	-150	+150	+150	+150	μV/V
	ΔV _{IO} /ΔV-		-150	-150	-150	+150	+150	+150	μV/V
Peak Output Voltage	V _{OM+}		12	12	12	15	15	15	V
Peak Output Voltage	V _{OM-}		-15	-15	-15	-12	-12	-12	V
Amplifier Supply Current	I _A		—	—	—	1500	1200	1500	μA
Zener Bias Regulator									
Zener Voltage	V _Z	I _Z = 100 μA	5.9	6.2	5.9	8.2	7.9	8.2	V
Zener Voltage	V _Z	I _Z = 1 mA	5.9	6.3	6.0	8.2	8.0	8.2	V

* (each ampl.)



Functional block diagram.

CA3060A/...**TABLE B. DELTA LIMITS** at $T_A = 25^\circ\text{C}$, $V^+ = +15\text{ V}$, $V^- = -15\text{ V}$, $I_{ABC} = 100\text{ }\mu\text{A}$ (/1 only)

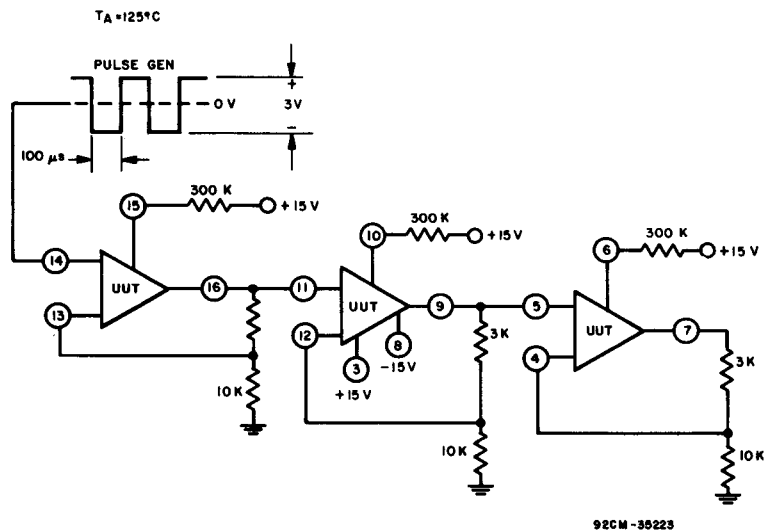
CHARACTERISTIC		LIMITS	UNITS
		MAX. Δ	
Input Offset Voltage	V_{IO}	± 0.15	mV
Input Offset Current	I_{IO}	± 50	nA
Input Bias Current	I_{IB}	± 250	nA

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TABLE C. GROUPS C AND D END-POINT TESTS at $T_A = 25^\circ\text{C}$, $V^+ = +15\text{ V}$, $V^- = -15\text{ V}$, $I_{ABC} = 100\text{ }\mu\text{A}$

CHARACTERISTIC		LIMITS		UNITS
		MIN.	MAX.	
Input Offset Voltage	V_{IO}	-10	+10	mV
Input Offset Current	I_{IO}	-2000	+2000	nA
Input Bias Current	I_{IB}	—	9000	nA
Peak Output Voltage	V_{OM+}	10	15	V
Peak Output Voltage	V_{OM-}	-15	-10	V
Amplifier Supply Current (each amp)	I_A	—	1500	μA

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Burn-in and operating life-test circuit.